

### Qualification Report for PCN# 20121015004 Qualification of TI Malaysia as Additional Assembly and Test Site for select Devices on the SSOP package Information Only

Date:

Dear Customer:

Texas Instruments is pleased to announce the completion of qualification testing for the product change described in PCN# 20121015004. The details of the qualification results are included in the following pages and are being forwarded to you in response to your inquiry about this PCN.

For questions regarding this notice, contact your local Field Sales Representative or the PCN Manager (<u>PCN\_ww\_admin\_team@list.ti.com</u>).

Sincerely,

PCN Team SC Business Services Phone: +1(214) 480-6037 Fax: +1(214) 480-6659



## Qualification Report For # 20121015004 Qualification of TI Malaysia as Additional Assembly and Test Site for select Devices on the SSOP package

# **Qualification Data:**

This qualification has been specifically developed for the validation of this change. The qualification data validates that the proposed change meets the applicable released technical specifications.

#### Qual Vehicle 1: PCM1803ADBR (MSL 1-260C)

Package Construction Details							
Assembly Site:	TI-MLA	Mold Compound:		4211880			
# Pins-Designator, Family:	20-DB, SSOP	Mount Compound:		4042500			
Leadframe (Finish, Base):	NiPdAu, Cu	Bond Wire Diameter:		0.96 Mil, Au			
Qualification: 🗌 Plan 🛛 Test Results							
Reliability Test	Conditions	Sample Size / Fail					
Moisture Sensitivity	(level 1 @ 260C peak +5/-0	0C)		12/0			
Ball Bond Shear	76 wires, min 3 devices	76/0		76/0			
Bond Pull		76/0					
Manufacturability		Pass					

# **Reference Qualifications:**

Qualification Data: Approved 10/18/2012									
This qualification has been specifically developed for the validation of this change. The qualification data validates that the proposed change meets the applicable released technical specifications.						n data			
Qual Vehicle 1: SN65LVCP22DR (MSL 1-260C)									
Package Construction Details									
Assembly	Site: 1	te: TI-TAI		Mold Com	Mold Compound:		4211880		
# Pins-Designator, Fa	mily: 1	: 10-DQC, WSON		Mount Com	oound:	4042500			
Leadframe (Finish, B	ase): N	: NiPdAu, Cu Bond		Bond Wire Dia	meter:	0.96 Mil, Au			
Qualification: 🗌 Plan 🖾 Test Results									
Reliability Test		Conditions	Conditions		Sample Size / Fail				
		Conditions			Lot 1	Lot 2	Lot 3		
**High Temp. Storage Bake		170C (420h	70C (420hrs)		77/0	77/0	77/0		
**Autoclave 121C		121C, 2 ATI	121C, 2 ATM (240 hrs)		77/0	77/0	77/0		
**T/C -65C/150C		-65C/+150	С (1000 Сус)		77/0	77/0	77/0		
Manufacturability (Assembly MQ)		) (per mfg. S	(per mfg. Site specification)		PASS	PASS	PASS		
Notes: **- Preconditioning Sequence: L1-260C									
Qual Vehicle 2: SN75976A1DL (MSL 2-260C)									
Package Construction Details									
Assembly Site:	TI-MLA	MLA		Mold Compound:	4211880				
# Pins-Designator, Family:	56-DL,	56-DL, SSOP		Mount Compound:	4042500				

Leadframe (Finish, Base): NiPdAu, Cu Bond Wire Diameter: 0.96 Mil, Au							
Qualification: 🗌 Plan 🛛 Test Results							
Poliability Test		Conditions		Sample Size / Fail			
Reliability Test		Conditions		Lot 1	Lot 2	Lot 3	
**High Temp. Storage Bake		170C (420 hrs)		77/0	77/0	77/0	
**Autoclave 121C		121C, 2 ATM (9	96 hrs)	77/0	77/0	77/0	
**T/C -65C/150C		-65C/+150C (5	500 Cyc)	77/0	77/0	77/0	
Moisture Sensitivity		(level 2 @ 260C peak +5/-0C)		12/0	-	-	
Manufacturability		(per mfg. Site specification) PASS PASS PASS			PASS		
Notes: **- Preconditioning S	Sequ	uence: L2-2600					
Qual	/eh	icle 3: TL145	4ACDBR (MSL1-260	C)			
	P	ackage Const	ruction Details				
Assembly Site:	TI-	-MLA	4211880				
# Pins-Designator, Family:	16	6-DB, SSOP Mount Compound:		4042500			
Leadframe (Finish, Base):	NiF	PdAu, Cu	Bond Wire:	0.8 Mil, Au			
Qualification:  Plan	Т 🛛	est Results					
Delighility Test		Conditions		Sam	ple Size /	Fail	
Reliability Test		Conditions		Lot 1	Lot 2	Lot 3	
**High Temp. Storage Bake		170C (420hrs	s)	77/0	77/0	73/0	
**Autoclave 121C		121C, 2 ATM	(96 hrs)	77/0	77/0	77/0	
**T/C -65C/150C		-65C/+150C (2000 Cyc)		77/0	77/0	77/0	
Moisture Sensitivity		(level 1 @ 26	el 1 @ 260C peak +5/-0C) 12/0 12/0		12/0	12/0	
Manufacturability (Assembly MQ)		(per mfg. Site	e specification)	PASS PASS PASS			
Notes: **- Preconditioning S	Sequ	uence: L1-2600	)				
Qual Ve	hicl	e 4: TLC320A	D77CDBR (MSL 1-2	60C)			
Package Construction Details							
Assembly Site: TI-M		-MLA	Mold Compound:	4211880			
# Pins-Designator, Family: 28-I		-DB, SOIC	Mount Compound:	d: 4042500			
Leadframe (Finish, Base): NiPo		PdAu, Cu	Bond Wire:	1.20 Mil Dia., Au			
Qualification: Plan I Test Results							
Delighility Teet		Conditions		Sample Size / Fail			
Reliability Test		Conditions		Lot 1	Lot 2	Lot 3	
**High Temp. Storage Bake		170C (420 hrs)		77/0	77/0	77/0	
**Autoclave 121C		121C, 2 ATM	121C, 2 ATM (96 hrs)		77/0	77/0	
**T/C -65C/150C		-65C/+150C	+150C (1000 Cyc)		77/0	77/0	
Moisture Sensitivity		(level 1 @ 26	@ 260C peak +5/-0C) 12/		-	-	
Manufacturability		(per mfg. Site	(per mfg. Site specification)		PASS	PASS	
Notes: **- Preconditioning Sequence: L1-260C							
Qual Vehicle 5: TPA4860DR (MSL 1-260C)							
Package Construction Details							
Assembly Site:	TI-	-TAI	Mold Compound:	421188	30		
# Pins-Designator, Family:	16	-D, SOIC	Mount Compound:	4042500			
Leadframe (Finish, Base):	Ni	iPdAu, Cu Bond		1.15 Mil Dia., Au			
Qualification: 🗌 Plan 🛛 Test Results							
Reliability Test	Conditions	Sample Size / Fail		Fail			
**Autoclave 121C		121C, 2 ATM	(96 hrs)	77/0			
**T/C -65C/150C		-65C/+150C	(500 Cyc)	77/0			
Moisture Sensitivity		(level 1 @ 26	oOC peak +5/-0C)	12/0			
Manufacturability		(ner mfa Sit	e specification)	PASS			

### Notes: \*\*- Preconditioning Sequence: L1-260C

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com